NL17SHT126

Noninverting Buffer / CMOS Logic Level Shifter with LSTTL-Compatible Inputs

The NL17SHT126 is a single gate noninverting 3-state buffer fabricated with silicon gate CMOS technology. It achieves high speed operation similar to equivalent Bipolar Schottky TTL while maintaining CMOS low power dissipation.

The NL17SHT126 requires the 3-state control input (OE) to be set Low to place the output into the high impedance state.

The device input is compatible with TTL-type input thresholds and the output has a full 5 V CMOS level output swing. The input protection circuitry on this device allows overvoltage tolerance on the input, allowing the device to be used as a logic-level translator from 3 V CMOS logic to 5 V CMOS Logic or from 1.8 V CMOS logic to 3 V CMOS Logic while operating at the high-voltage power supply.

The NL17SHT126 input structure provides protection when voltages up to 7 V are applied, regardless of the supply voltage. This allows the NL17SHT126 to be used to interface 5 V circuits to 3 V circuits. The output structures also provide protection when $V_{CC} = 0$ V. These input and output structures help prevent device destruction caused by supply voltage – input/output voltage mismatch, battery backup, hot insertion, etc.

Features

- High Speed: $t_{PD} = 3.5 \text{ ns} (Typ) \text{ at } V_{CC} = 5 \text{ V}$
- Low Power Dissipation: $I_{CC} = 1 \ \mu A \ (Max)$ at $T_A = 25^{\circ}C$
- TTL-Compatible Inputs: $V_{IL} = 0.8 V$; $V_{IH} = 2 V$
- CMOS–Compatible Outputs: $V_{OH} > 0.8 V_{CC}$; $V_{OL} < 0.1 V_{CC}$ @Load
- Power Down Protection Provided on Inputs and Outputs
- Balanced Propagation Delays
- Pin and Function Compatible with Other Standard Logic Families
- These are Pb–Free Devices

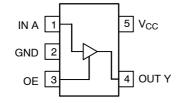


Figure 1. Pinout (Top View)



Figure 2. Logic Symbol



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MARKING DIAGRAM



R = Specific Device Code M = Month Code

PIN ASSIGNMENT							
1 IN A							
2 GND							
3 OE							
4	OUT Y						
5 V _{CC}							

FUNCTION TABLE

A Input	OE Input	Y Output
L	н	L
Н	н	Н
Х	L	Z

ORDERING INFORMATION

See detailed ordering and shipping information in the package dimensions section on page 4 of this data sheet.

MAXIMUM RATINGS

Symbol	Characteristics	Value	Unit
V _{CC}	DC Supply Voltage	–0.5 to +7.0	V
V _{IN}	DC Input Voltage	–0.5 to +7.0	V
V _{OUT}	DC Output Voltage	–0.5 to V _{CC} + 0.5	V
I _{IK}	Input Diode Current	-20	mA
I _{OK}	$\label{eq:output} Output \ Diode \ Current \qquad \qquad V_{OUT} < GND; \ V_{OUT} > V_{CC}$	±20	mA
I _{OUT}	DC Output Current	±25	mA
I _{CC}	DC Supply Current, V _{CC} and GND	50	mA
PD	Power Dissipation in Still Air	50	mW
ΤL	Lead Temperature, 1 mm from Case for 10 s	260	°C
TJ	Junction Temperature Under Bias	+150	°C
T _{stg}	Storage Temperature	-65 to +150	°C
I _{Latchup}	Latchup Performance Above V _{CC} and Below GND at 125°C (Note 1)	±100	mA

Stresses exceeding Maximum Ratings may damage the device. Maximum Ratings are stress ratings only. Functional operation above the Recommended Operating Conditions is not implied. Extended exposure to stresses above the Recommended Operating Conditions may affect device reliability.

1. Tested to EIA/JESD78

RECOMMENDED OPERATING CONDITIONS

Symbol	Characteristics	Min	Max	Unit
V _{CC}	DC Supply Voltage	3.0	5.5	V
V _{IN}	DC Input Voltage	0.0	5.5	V
V _{OUT}	DC Output Voltage	0.0	V _{CC}	V
T _A	Operating Temperature Range	-55	+125	°C
t _r , t _f	Input Rise and Fall Time $$V_{CC}$$ = 5.0 V \pm 0.5 V	0	20	ns/V

Device Junction Temperature versus Time to 0.1% Bond Failures

Junction Temperature °C	Time, Hours	Time, Years
80	1,032,200	117.8
90	419,300	47.9
100	178,700	20.4
110	79,600	9.4
120	37,000	4.2
130	17,800	2.0
140	8,900	1.0

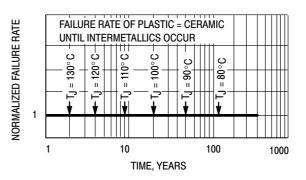


Figure 3. Failure Rate vs. Time Junction Temperature

NL17SHT126

DC ELECTRICAL CHARACTERISTICS

			V _{CC}	٦	Γ _A = 25°	°C	T _A ≤	85°C	$-55 \leq T_{A} \leq 125^{\circ}C$					
Symbol	Symbol	Parameter	Parameter	Test Conditions	Test Conditions	(V)	Min	Тур	Max	Min	Max	Min	Max	Unit
V _{IH}	Minimum High-Level Input Voltage		3.0 4.5 5.5	1.4 2.0 2.0			1.4 2.0 2.0		1.4 2.0 2.0		V			
V _{IL}	Maximum Low-Level Input Voltage		3.0 4.5 5.5			0.53 0.8 0.8		0.53 0.8 0.8		0.53 0.8 0.8	V			
V _{OH}	Minimum High-Level Output Voltage		3.0 4.5	2.9 4.4	3.0 4.5		2.9 4.4		2.9 4.4		V			
V _{IN} = V _{IH} or V _{IL}	$v_{IN} = v_{IH} \text{ or } v_{IL}$		3.0 4.5	2.58 3.94			2.48 3.80		2.34 3.66					
V _{OL}	Maximum Low-Level Output Voltage	$V_{IN} = V_{IH} \text{ or } V_{IL}$ $I_{OL} = 50 \ \mu A$	3.0 4.5		0.0 0.0	0.1 0.1		0.1 0.1		0.1 0.1	V			
	$V_{IN} = V_{IH} \text{ or } V_{IL}$	$V_{IN} = V_{IH} \text{ or } V_{IL}$ $I_{OL} = 4 \text{ mA}$ $I_{OL} = 8 \text{ mA}$	3.0 4.5			0.36 0.36		0.44 0.44		0.52 0.52				
I _{IN}	Maximum Input Leak- age Current	V _{IN} = 5.5 V or GND	0 to 5.5			±0.1		±1.0		± 1.0	μA			
I _{CC}	Maximum Quiescent Supply Current	$V_{IN} = V_{CC}$ or GND	5.5			1.0		20		40	μA			
I _{CCT}	Quiescent Supply Current	Input: V _{IN} = 3.4 V Other Input: V _{CC} or GND	5.5			1.35		1.50		1.65	mA			
I _{OPD}	Output Leakage Current	V _{OUT} = 5.5 V	0.0			0.5		5.0		10	μA			
I _{OZ}	Maximum 3-State Leakage Current	$V_{IN} = V_{IH} \text{ or } V_{IL}$ $V_{OUT} = V_{CC} \text{ or } GND$	5.5			± 0.25		± 2.5		± 2.5	μA			

AC ELECTRICAL CHARACTERISTICS Input $t_r = t_f = 3.0 \text{ ns}$

				Т	A = 25°	С	T _A ≤	85°C	-55 ≤ T _A	≤ 125°C	
Symbol	Parameter	Test Condi	tions	Min	Тур	Max	Min	Max	Min	Max	Unit
t _{PLH} , t _{PHL}	Maximum Propagation Delay, A to Y	$V_{CC} = 3.3 \pm 0.3 \text{ V}$	$C_L = 15pF$ $C_L = 50pF$		5.6 8.1	8.0 11.5	1.0 1.0	9.5 13.0		12.0 16.0	ns
	(Figures 3 and 5)	$V_{CC} = 5.0 \pm 0.5 \text{ V}$	$C_L = 15 pF$ $C_L = 50 pF$		3.8 5.3	5.5 7.5	1.0 1.0	6.5 8.5		8.5 10.5	
t _{PZL} , t _{PZH}	Maximum Output Enable Time, OE to Y	$\begin{array}{c} V_{CC} = 3.3 \pm 0.3 \ V \\ R_L = R_l = 500 \ \Omega \end{array}$	$C_L = 15 pF$ $C_L = 50 pF$		5.4 7.9	8.0 11.5	1.0 1.0	9.5 13.0		11.5 15.0	ns
	(Figures 4 and 5)	$\begin{array}{l} V_{CC} = 5.0 \pm 0.5 \; V \\ R_L = R_{I} = 500 \; \Omega \end{array}$			3.6 5.1	5.1 7.1	1.0 1.0	6.0 8.0		7.5 9.5	
t _{PLZ} , t _{PHZ}	Maximum Output Disable Time,OE to Y	$\begin{array}{c} V_{CC} = 3.3 \pm 0.3 \ V \\ R_L = R_l = 500 \ \Omega \end{array}$			6.5 8.0	9.7 13.2	1.0 1.0	11.5 15.0		14.5 18.0	ns
	(Figures 4 and 5)	$\begin{array}{l} V_{CC} = 5.0 \pm 0.5 \; V \\ R_L = R_{I} = 500 \; \Omega \end{array}$			4.8 7.0	6.8 8.8	1.0 1.0	8.0 10.0		10.0 12.0	
C _{in}	Maximum Input Capacitance				4	10		10		10	pF
C _{out}	Maximum Three–State Output Capacitance (Output in High Impedance State)				6						pF
	Typical @ 25°C, V _{CC} = 5.0 V					/					
C _{PD}	Power Dissipation Capacitance (Note 2)							14			pF

2. C_{PD} is defined as the value of the internal equivalent capacitance which is calculated from the operating current consumption without load. Average operating current can be obtained by the equation: $I_{CC(OPR)} = C_{PD} \bullet V_{CC} \bullet f_{in} + I_{CC}/4$ (per buffer). C_{PD} is used to determine the no-load dynamic power consumption; $P_D = C_{PD} \bullet V_{CC}^2 \bullet f_{in} + I_{CC} \bullet V_{CC}$.

NL17SHT126

SWITCHING WAVEFORMS

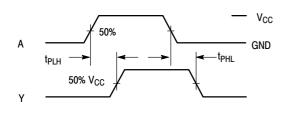
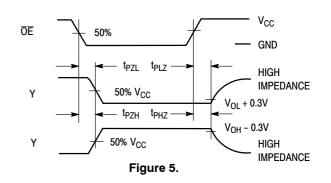
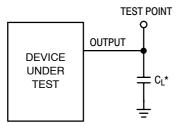


Figure 4. Switching Waveforms





*Includes all probe and jig capacitance



*Includes all probe and jig capacitance

CONNECT TO V_{CC} WHEN

TESTING t_{PLZ} AND t_{PZL}. CONNECT TO GND WHEN

TESTING tPHZ AND tPZH.

TEST POINT

OUTPUT

DEVICE

UNDER

TEST

 $1 k\Omega$

 C_L^*

Figure 7. Test Circuit

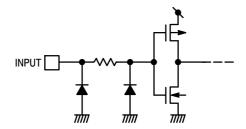


Figure 8. Input Equivalent Circuit

ORDERING INFORMATION

Device	Package	Shipping [†]
NL17SHT126P5T5G	SOT-953 (Pb-Free)	8000 / Tape & Reel

+For information on tape and reel specifications, including part orientation and tape sizes, please refer to our Tape and Reel Packaging Specifications Brochure, BRD8011/D.

SCALE 4:1

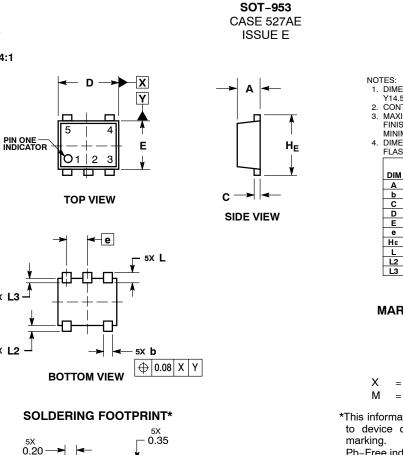
5X L3

5X L2

PACKAGE OUTLINE

0.35 PITCH





DATE 02 AUG 2011

NOTES: 1. DIMENSIONING AND TOLERANCING PER ASME Y14.5M, 1994. 2. CONTROLLING DIMENSION: MILLIMETERS 3. MAXIMUM LEAD THICKNESS INCLUDES LEAD FINISH. MINIMUM LEAD THICKNESS IS THE MINIMUM THICKNESS OF THE BASE MATERIAL. 4. DIMENSIONS D AND E DO NOT INCLUDE MOLD FLASH, PROTRUSIONS, OR GATE BURRS.

	MILLIMETERS								
DIM	MIN NOM MAX								
Α	0.34	0.37	0.40						
b	0.10	0.15	0.20						
С	0.07	0.17							
D	0.95 1.00	1.00	1.05						
E	0.75	0.80	0.85						
е		0.35 BS	С						
ΗE	0.95	1.00	1.05						
L	(0.175 RE	F						
L2	0.05	0.10	0.15						
L3			0.15						

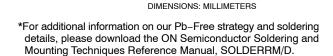
GENERIC **MARKING DIAGRAM***

= Specific Device Code

= Month Code

*This information is generic. Please refer to device data sheet for actual part

Pb-Free indicator, "G" or microdot " .", may or may not be present.



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1.20

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